


Search Notes 	Application/Control No. 10521173	Applicant(s)/Patent Under Reexamination OKUYAMA ET AL.
	Examiner ANDREW P BAINBRIDGE	Art Unit 3754

SEARCHED			
Class	Subclass	Date	Examiner
222	192	3/31/08	APB
250	281-282,286-288,423f,423p,423r,424,435	10/20/2008	APB
378	66,119,210	10/20/2008	APB
361	225-228, 230-235	10/20/2008	APB

SEARCH NOTES		
Search Notes	Date	Examiner
Reviewed all IDS	3/31/08	APB
Angstrom and Nanometer	3/28/08	APB
Soft X Ray	3/28/08	APB
Backwards/ forward searched relevant references	10/20/2008	APB
Updated all previous searches	12/31/2008	APB
"x-ray emitting" and "chamber" and "rectifying plate"	12/31/2008	APB
Interference search with "chamber" and "electric field" and "x-ray" and duct	1/5/2009	APB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
378	66	1/5/2009	APB
250	423r	1/5/2009	APB

/A. P. B./
Examiner, Art Unit 3754